EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	138	defect and (cmp or chemical adj mechanical adj polishing) and data adj base and yield	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:44
S2	90	killer and S1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/11 11:46
S3	413	(438/5).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/06 11:04
S4	2092	(438/14).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/06 11:04
S5	0	(defect and (inspect or inspected or inspection) and (classify or classification) and (adjust or adjusting) and sampling adj ratio).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:18
S6	3	(sampling adj ration).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:19
S7	5	xenon adj implantation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 15:01
S8	2	krypton adj implantation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:46

EAST Search History

S9	77	argon adj implantation	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:46
S10	89410	mosfet	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:46
S11	23	S9 and S10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 14:46
S12	32	("5192697").URPN.	USPAT	OR	ON	2006/04/06 14:58
S13	7	("4613402" | "5276347" | "5393676" | "5468974" | "5514902" | "5633177" | "5796166").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/04/06 15:00
S14	10	xenon adj implant	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/06 15:01